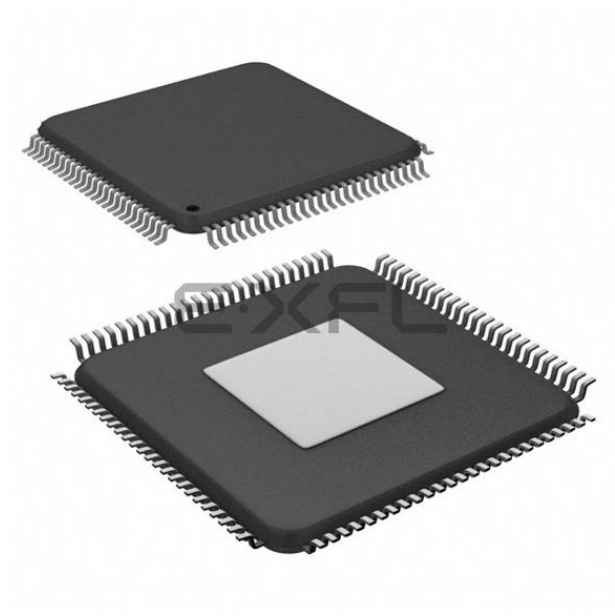
Infineon Technologies - XE164F24F66LACFXQMA1 Datasheet



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"Embedded - Microcontrollers" refer to small, integrated circuits designed to perform specific tasks within larger systems. These microcontrollers are essentially compact computers on a single chip, containing a processor core, memory, and programmable input/output peripherals. They are called "embedded" because they are embedded within electronic devices to control various functions, rather than serving as standalone computers. Microcontrollers are crucial in modern electronics, providing the intelligence and control needed for a wide range of applications.

Applications of "Embedded - Microcontrollers"

Details	
Product Status	Not For New Designs
Core Processor	C166SV2
Core Size	16-Bit
Speed	66MHz
Connectivity	CANbus, EBI/EMI, I²C, LINbus, SPI, SSC, UART/USART, USI
Peripherals	I²S, POR, PWM, WDT
Number of I/O	75
Program Memory Size	192KB (192K x 8)
Program Memory Type	FLASH
EEPROM Size	-
RAM Size	24K x 8
Voltage - Supply (Vcc/Vdd)	3V ~ 5.5V
Data Converters	A/D 16x10b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 85°C (TA)
Mounting Type	Surface Mount
Package / Case	100-LQFP Exposed Pad
Supplier Device Package	PG-LQFP-100-3
Purchase URL	https://www.e-xfl.com/product-detail/infineon-technologies/xe164f24f66lacfxqma1

2) Specific inormation about the on-chip Flash memory in **Table 2**.
3) All derivatives additionally provide 1 Kbyte SBRAM, 2 Kbytes DPRAM, and 16 Kbytes DSRAM (12 Kbytes for devices with 192 Kbytes of Flash).
4) Specific information about the available channels in **Table 3**.
Analog input channels are listed for each Analog/Digital Converter module separately (ADC0 + ADC1).

2 General Device Information

The XE164 series of real time signal controllers is a part of the Infineon XE166 Family of full-feature single-chip CMOS microcontrollers. These devices extend the functionality and performance of the C166 Family in terms of instructions (MAC unit), peripherals, and speed. They combine high CPU performance (up to 80 million instructions per second) with extended peripheral functionality and enhanced IO capabilities. Optimized peripherals can be adapted flexibly to meet the application requirements. These derivatives utilize clock generation via PLL and internal or external clock sources. On-chip memory modules include program Flash, program RAM, and data RAM.

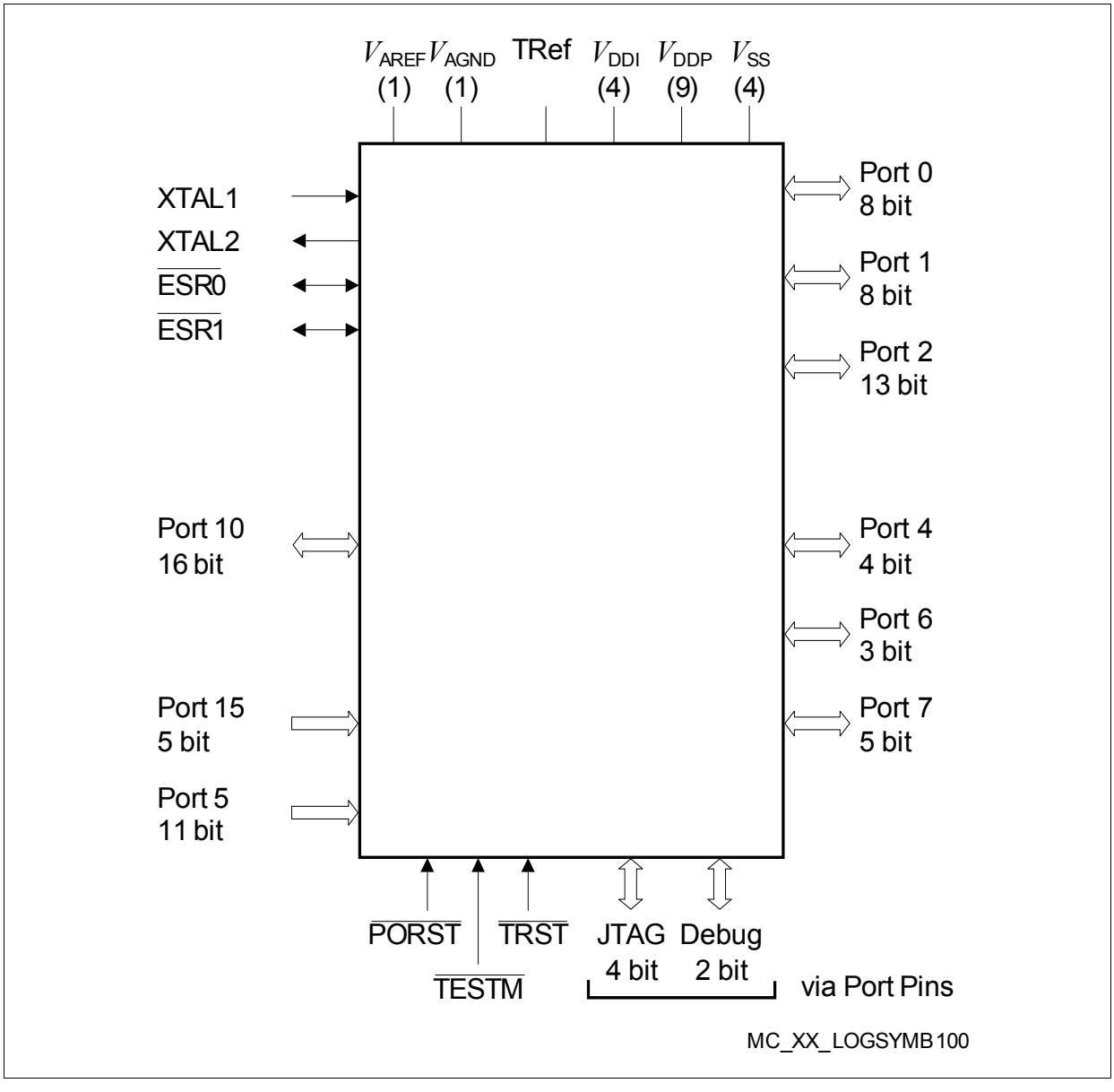

Figure 1 Logic Symbol

Table 4 Pin Definitions and Functions (cont'd)

Pin	Symbol	Ctrl.	Type	Function
35	P5.15	I	In/A	**Bit 15 of Port 5, General Purpose Input**
	ADC0_CH15	I	In/A	**Analog Input Channel 15 for ADC0**
36	P2.12	O0 / I	St/B	**Bit 12 of Port 2, General Purpose Input/Output**
	U0C0_ SELO4	O1	St/B	**USIC0 Channel 0 Select/Control 4 Output**
	U0C1_ SELO3	O2	St/B	**USIC0 Channel 1 Select/Control 3 Output**
	READY	I	St/B	**External Bus Interface READY Input**
37	P2.11	O0 / I	St/B	**Bit 11 of Port 2, General Purpose Input/Output**
	U0C0_ SELO2	O1	St/B	**USIC0 Channel 0 Select/Control 2 Output**
	U0C1_ SELO2	O2	St/B	**USIC0 Channel 1 Select/Control 2 Output**
	$\overline{BHE}$/$\overline{WRH}$	OH	St/B	**External Bus Interf. High-Byte Control Output** Can operate either as Byte High Enable ($\overline{BHE}$) or as Write strobe for High Byte ($\overline{WRH}$).
39	P2.0	O0 / I	St/B	**Bit 0 of Port 2, General Purpose Input/Output**
	AD13	OH / I	St/B	**External Bus Interface Address/Data Line 13**
	RxDC0C	I	St/B	**CAN Node 0 Receive Data Input**
40	P2.1	O0 / I	St/B	**Bit 1 of Port 2, General Purpose Input/Output**
	TxDC0	O1	St/B	**CAN Node 0 Transmit Data Output**
	AD14	OH / I	St/B	**External Bus Interface Address/Data Line 14**
	ESR1_5	I	St/B	**ESR1 Trigger Input 5**
	EX0AINA	I	St/B	**External Interrupt Trigger Input**
41	P2.2	O0 / I	St/B	**Bit 2 of Port 2, General Purpose Input/Output**
	TxDC1	O1	St/B	**CAN Node 1 Transmit Data Output**
	AD15	OH / I	St/B	**External Bus Interface Address/Data Line 15**
	ESR2_5	I	St/B	**ESR2 Trigger Input 5**
	EX1AINA	I	St/B	**External Interrupt Trigger Input**
42	P4.0	O0 / I	St/B	**Bit 0 of Port 4, General Purpose Input/Output**
	CC2_24	O3 / I	St/B	**CAPCOM2 CC24IO Capture Inp./ Compare Out.**
	$\overline{CS0}$	OH	St/B	**External Bus Interface Chip Select 0 Output**

This common memory space consists of 16 Mbytes organized as 256 segments of 64 Kbytes; each segment contains four data pages of 16 Kbytes. The entire memory space can be accessed bytewise or wordwise. Portions of the on-chip DPRAM and the register spaces (ESFR/SFR) additionally are directly bit addressable.

The internal data memory areas and the Special Function Register areas (SFR and ESFR) are mapped into segment 0, the system segment.

The Program Management Unit (PMU) handles all code fetches and, therefore, controls access to the program memories such as Flash memory and PSRAM.

The Data Management Unit (DMU) handles all data transfers and, therefore, controls access to the DSRAM and the on-chip peripherals.

Both units (PMU and DMU) are connected to the high-speed system bus so that they can exchange data. This is required if operands are read from program memory, code or data is written to the PSRAM, code is fetched from external memory, or data is read from or written to external resources. These include peripherals on the LXBus such as USIC or MultiCAN. The system bus allows concurrent two-way communication for maximum transfer performance.

Up to 64 Kbytes of on-chip Program SRAM (PSRAM) are provided to store user code or data. The PSRAM is accessed via the PMU and is optimized for code fetches. A section of the PSRAM with programmable size can be write-protected.

*Note: The actual size of the PSRAM depends on the chosen derivative (see **Table 1**).*

Up to 16 Kbytes of on-chip Data SRAM (DSRAM) are used for storage of general user data (12 Kbytes for devices with 192 Kbytes of Flash). The DSRAM is accessed via a separate interface and is optimized for data access.

2 Kbytes of on-chip Dual-Port RAM (DPRAM) provide storage for user-defined variables, for the system stack, and for general purpose register banks. A register bank can consist of up to 16 word-wide (R0 to R15) and/or byte-wide (RL0, RH0, …, RL7, RH7) General Purpose Registers (GPRs).
The upper 256 bytes of the DPRAM are directly bit addressable. When used by a GPR, any location in the DPRAM is bit addressable.

1 Kbyte of on-chip Stand-By SRAM (SBRAM) provides storage for system-relevant user data that must be preserved while the major part of the device is powered down. The SBRAM is accessed via a specific interface and is powered in domain M.

3.3 Central Processing Unit (CPU)

The core of the CPU consists of a 5-stage execution pipeline with a 2-stage instruction-fetch pipeline, a 16-bit arithmetic and logic unit (ALU), a 32-bit/40-bit multiply and accumulate unit (MAC), a register-file providing three register banks, and dedicated SFRs. The ALU features a multiply-and-divide unit, a bit-mask generator, and a barrel shifter.

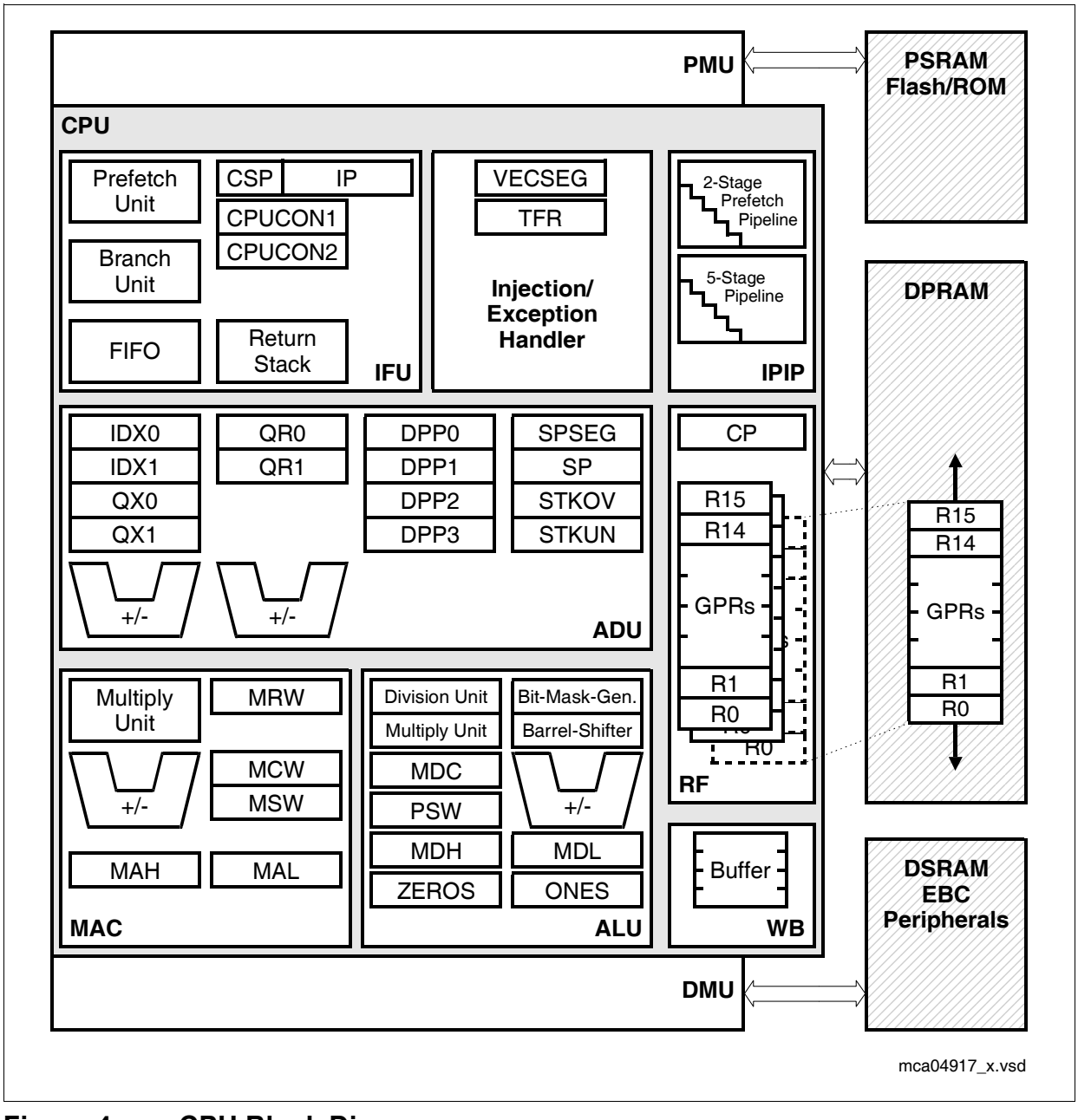

Figure 4 CPU Block Diagram

Table 6 XE164 Interrupt Nodes (cont'd)

Source of Interrupt or PEC Service Request	Control Register	Vector Location[1)]	Trap Number
GPT2 Timer 5	GPT12E_T5IC	xx'008C$_H$	23$_H$ / 35$_D$
GPT2 Timer 6	GPT12E_T6IC	xx'0090$_H$	24$_H$ / 36$_D$
GPT2 CAPREL Register	GPT12E_CRIC	xx'0094$_H$	25$_H$ / 37$_D$
CAPCOM Timer 7	CC2_T7IC	xx'0098$_H$	26$_H$ / 38$_D$
CAPCOM Timer 8	CC2_T8IC	xx'009C$_H$	27$_H$ / 39$_D$
A/D Converter Request 0	ADC_0IC	xx'00A0$_H$	28$_H$ / 40$_D$
A/D Converter Request 1	ADC_1IC	xx'00A4$_H$	29$_H$ / 41$_D$
A/D Converter Request 2	ADC_2IC	xx'00A8$_H$	2A$_H$ / 42$_D$
A/D Converter Request 3	ADC_3IC	xx'00AC$_H$	2B$_H$ / 43$_D$
A/D Converter Request 4	ADC_4IC	xx'00B0$_H$	2C$_H$ / 44$_D$
A/D Converter Request 5	ADC_5IC	xx'00B4$_H$	2D$_H$ / 45$_D$
A/D Converter Request 6	ADC_6IC	xx'00B8$_H$	2E$_H$ / 46$_D$
A/D Converter Request 7	ADC_7IC	xx'00BC$_H$	2F$_H$ / 47$_D$
CCU60 Request 0	CCU60_0IC	xx'00C0$_H$	30$_H$ / 48$_D$
CCU60 Request 1	CCU60_1IC	xx'00C4$_H$	31$_H$ / 49$_D$
CCU60 Request 2	CCU60_2IC	xx'00C8$_H$	32$_H$ / 50$_D$
CCU60 Request 3	CCU60_3IC	xx'00CC$_H$	33$_H$ / 51$_D$
CCU61 Request 0	CCU61_0IC	xx'00D0$_H$	34$_H$ / 52$_D$
CCU61 Request 1	CCU61_1IC	xx'00D4$_H$	35$_H$ / 53$_D$
CCU61 Request 2	CCU61_2IC	xx'00D8$_H$	36$_H$ / 54$_D$
CCU61 Request 3	CCU61_3IC	xx'00DC$_H$	37$_H$ / 55$_D$
CCU62 Request 0	CCU62_0IC	xx'00E0$_H$	38$_H$ / 56$_D$
CCU62 Request 1	CCU62_1IC	xx'00E4$_H$	39$_H$ / 57$_D$
CCU62 Request 2	CCU62_2IC	xx'00E8$_H$	3A$_H$ / 58$_D$
CCU62 Request 3	CCU62_3IC	xx'00EC$_H$	3B$_H$ / 59$_D$
Unassigned node	–	xx'00F0$_H$	3C$_H$ / 60$_D$
Unassigned node	–	xx'00F4$_H$	3D$_H$ / 61$_D$
Unassigned node	–	xx'00F8$_H$	3E$_H$ / 62$_D$
Unassigned node	–	xx'00FC$_H$	3F$_H$ / 63$_D$
CAN Request 0	CAN_0IC	xx'0100$_H$	40$_H$ / 64$_D$

The XE164 includes an excellent mechanism to identify and process exceptions or error conditions that arise during run-time, the so-called ‘Hardware Traps’. A hardware trap causes an immediate non-maskable system reaction similar to a standard interrupt service (branching to a dedicated vector table location). The occurrence of a hardware trap is also indicated by a single bit in the trap flag register (TFR). Unless another higher-priority trap service is in progress, a hardware trap will interrupt any ongoing program execution. In turn, hardware trap services can normally not be interrupted by standard or PEC interrupts.

Table 7 shows all possible exceptions or error conditions that can arise during runtime:

Table 7 Trap Summary

Exception Condition	Trap Flag	Trap Vector	Vector Location[1)]	Trap Number	Trap Priority
Reset Functions	–	RESET	xx’0000$_H$	00$_H$	III
Class A Hardware Traps:					
• System Request 0	SR0	SR0TRAP	xx’0008$_H$	02$_H$	II
• Stack Overflow	STKOF	STOTRAP	xx’0010$_H$	04$_H$	II
• Stack Underflow	STKUF	STUTRAP	xx’0018$_H$	06$_H$	II
• Software Break	SOFTBRK	SBRKTRAP	xx’0020$_H$	08$_H$	II
Class B Hardware Traps:					
• System Request 1	SR1	BTRAP	xx’0028$_H$	0A$_H$	I
• Undefined Opcode	UNDOPC	BTRAP	xx’0028$_H$	0A$_H$	I
• Memory Access Error	ACER	BTRAP	xx’0028$_H$	0A$_H$	I
• Protected Instruction Fault	PRTFLT	BTRAP	xx’0028$_H$	0A$_H$	I
• Illegal Word Operand Access	ILLOPA	BTRAP	xx’0028$_H$	0A$_H$	I
Reserved	–	–	[2C$_H$ - 3C$_H$]	[0B$_H$ - 0F$_H$]	–
Software Traps: • TRAP Instruction	–	–	Any [xx’0000$_H$ - xx’01FC$_H$] in steps of 4$_H$	Any [00$_H$ - 7F$_H$]	Current CPU Priority

1) Register VECSEG defines the segment where the vector table is located to.
Bitfield VECSC in register CPUCON1 defines the distance between two adjacent vectors. This table represents the default setting, with a distance of 4 (two words) between two vectors.

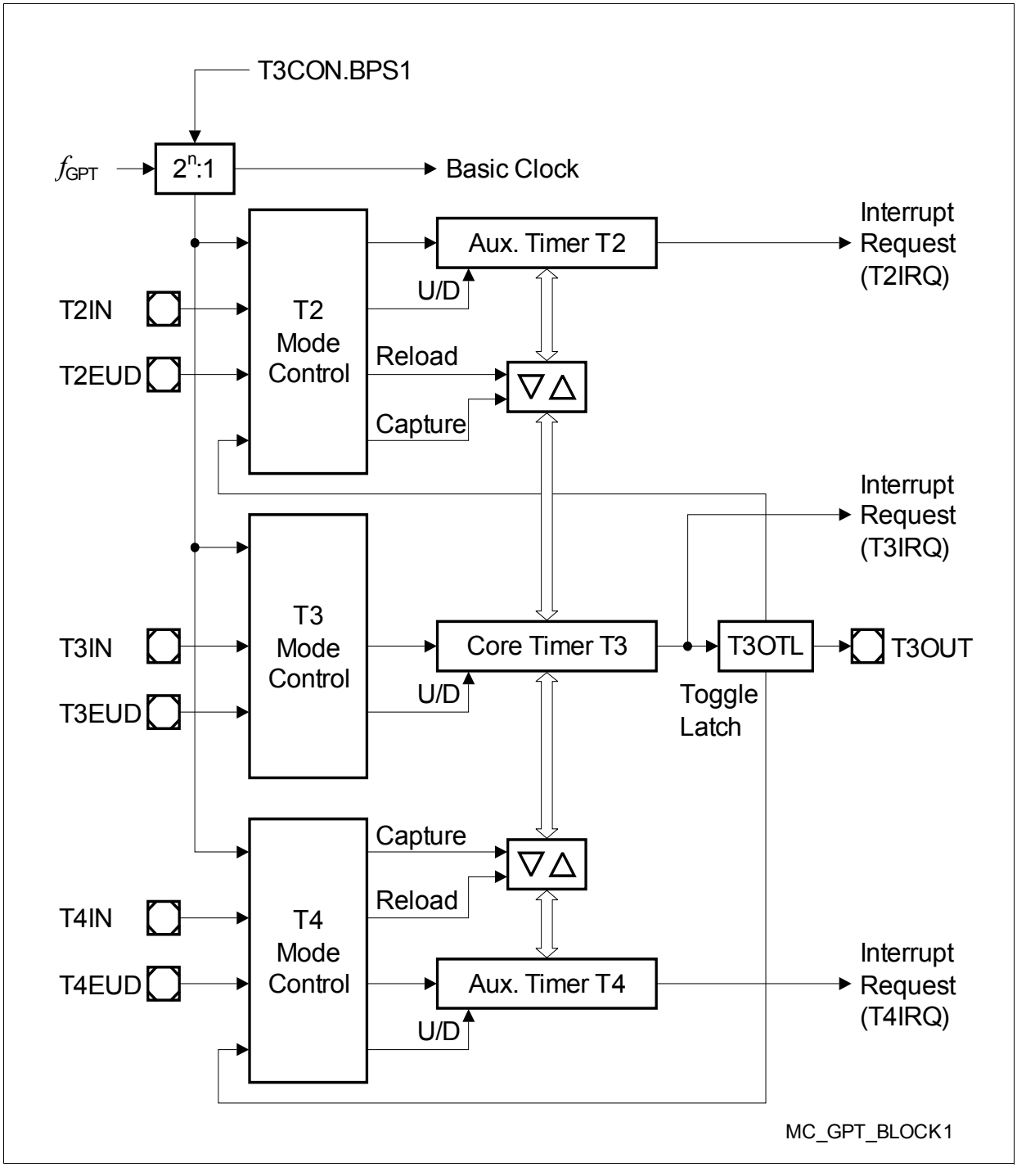

Figure 7 Block Diagram of GPT1

MultiCAN Features

- CAN functionality conforming to CAN specification V2.0 B active for each CAN node (compliant to ISO 11898)
- Up to four independent CAN nodes
- 128 independent message objects (shared by the CAN nodes)
- Dedicated control registers for each CAN node
- Data transfer rate up to 1 Mbit/s, individually programmable for each node
- Flexible and powerful message transfer control and error handling capabilities
- Full-CAN functionality for message objects:
  - Can be assigned to one of the CAN nodes
  - Configurable as transmit or receive objects, or as message buffer FIFO
  - Handle 11-bit or 29-bit identifiers with programmable acceptance mask for filtering
  - Remote Monitoring Mode, and frame counter for monitoring
- Automatic Gateway Mode support
- 16 individually programmable interrupt nodes
- Analyzer mode for CAN bus monitoring

Operating Conditions

The following operating conditions must not be exceeded to ensure correct operation of the XE164. All parameters specified in the following sections refer to these operating conditions, unless otherwise noticed.

Table 12 Operating Condition Parameters

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
Digital core supply voltage	V_{DDI}	1.4	–	1.6	V	
Core Supply Voltage Difference	ΔVDDI	-10	–	+10	mV	V_{DDIM} - V_{DDI1} 1)
Digital supply voltage for IO pads and voltage regulators, upper voltage range	V_{DDPA}, V_{DDPB}	4.5	–	5.5	V	2)
Digital supply voltage for IO pads and voltage regulators, lower voltage range	V_{DDPA}, V_{DDPB}	3.0	–	4.5	V	2)
Digital ground voltage	V_{SS}	0	–	0	V	Reference voltage
Overload current	I_{OV}	-5	–	5	mA	Per IO pin 3)4)
		-2	–	5	mA	Per analog input pin 3)4)
Overload positive current coupling factor for analog inputs 5)	K_{OVA}	–	1.0×10^{-6}	1.0×10^{-4}	–	$I_{OV} > 0$
Overload negative current coupling factor for analog inputs 5)	K_{OVA}	–	2.5×10^{-4}	1.5×10^{-3}	–	$I_{OV} < 0$
Overload positive current coupling factor for digital I/O pins 5)	K_{OVD}	–	1.0×10^{-4}	5.0×10^{-3}	–	$I_{OV} > 0$
Overload negative current coupling factor for digital I/O pins 5)	K_{OVD}	–	1.0×10^{-2}	3.0×10^{-2}	–	$I_{OV} < 0$
Absolute sum of overload currents	Σ|IOV|	–	–	50	mA	4)

4.2.1 DC Parameters for Upper Voltage Area

These parameters apply to the upper IO voltage range, 4.5 V ≤ V_{DDP} ≤ 5.5 V.

Table 14 DC Characteristics for Upper Voltage Range (Operating Conditions apply)[1)]

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
Input low voltage (all except XTAL1)	V_{IL} SR	-0.3	–	0.3 × V_{DDP}	V	–
Input high voltage (all except XTAL1)	V_{IH} SR	0.7 × V_{DDP}	–	V_{DDP} + 0.3	V	–
Input Hysteresis[2)]	HYS CC	0.11 × V_{DDP}	–	–	V	V_{DDP} in [V], Series resistance = 0 Ω
Output low voltage	V_{OL} CC	–	–	1.0	V	$I_{OL} \le I_{OLmax}$[3)]
Output low voltage	V_{OL} CC	–	–	0.4	V	$I_{OL} \le I_{OLnom}$[3)4)]
Output high voltage[5)]	V_{OH} CC	V_{DDP} - 1.0	–	–	V	$I_{OH} \ge I_{OHmax}$[3)]
Output high voltage[5)]	V_{OH} CC	V_{DDP} - 0.4	–	–	V	$I_{OH} \ge I_{OHnom}$[3)4)]
Input leakage current (Port 5, Port 15)[6)]	I_{OZ1} CC	–	±10	±200	nA	0 V < V_{IN} < V_{DDP}
Input leakage current (all other)[6)7)]	I_{OZ2} CC	–	±0.2	±5	µA	$T_J \le$ 110°C, 0.45 V < V_{IN} < V_{DDP}
Pull level keep current	I_{PLK}	–	–	±30	µA	$V_{PIN} \ge V_{IH}$ (up)[8)] $V_{PIN} \le V_{IL}$ (dn)
Pull level force current	I_{PLF}	±250	–	–	µA	$V_{PIN} \le V_{IL}$ (up)[8)] $V_{PIN} \ge V_{IH}$ (dn)
Pin capacitance[9)] (digital inputs/outputs)	C_{IO} CC	–	–	10	pF	

1) Keeping signal levels within the limits specified in this table ensures operation without overload conditions. For signal levels outside these specifications, also refer to the specification of the overload current I_{OV}.

2) Not subject to production test - verified by design/characterization. Hysteresis is implemented to avoid metastable states and switching due to internal ground bounce. It cannot suppress switching due to external system noise under all conditions.

3) The maximum deliverable output current of a port driver depends on the selected output driver mode, see **Table 13**, **Current Limits for Port Output Drivers**. The limit for pin groups must be respected.

4) As a rule, with decreasing output current the output levels approach the respective supply level ($V_{OL} \rightarrow V_{SS}$, $V_{OH} \rightarrow V_{DDP}$). However, only the levels for nominal output currents are verified.
5) This specification is not valid for outputs which are switched to open drain mode. In this case the respective output will float and the voltage is determined by the external circuit.
6) An additional error current (I_{INJ}) will flow if an overload current flows through an adjacent pin. Please refer to the definition of the overload coupling factor K_{OV}.
7) The given values are worst-case values. In production test, this leakage current is only tested at 125°C; other values are ensured by correlation. For derating, please refer to the following descriptions:
Leakage derating depending on temperature (T_J = junction temperature [°C]):
$I_{OZ} = 0.05 \times e^{(1.5 + 0.028 \times TJ)}$ [µA]. For example, at a temperature of 95°C the resulting leakage current is 3.2 µA.
Leakage derating depending on voltage level (DV = V_{DDP} - V_{PIN} [V]):
$I_{OZ} = I_{OZtempmax}$ - (1.6 × DV) [µA]
This voltage derating formula is an approximation which applies for maximum temperature.
Because pin P2.8 is connected to two pads (standard pad and high-speed clock pad), it has twice the normal leakage.
8) Keep current: Limit the current through this pin to the indicated value so that the enabled pull device can keep the default pin level: $V_{PIN} \geq V_{IH}$ for a pullup; $V_{PIN} \leq V_{IL}$ for a pulldown.
Force current: Drive the indicated minimum current through this pin to change the default pin level driven by the enabled pull device: $V_{PIN} \leq V_{IL}$ for a pullup; $V_{PIN} \geq V_{IH}$ for a pulldown.
These values apply to the fixed pull-devices in dedicated pins and to the user-selectable pull-devices in general purpose IO pins.
9) Not subject to production test - verified by design/characterization.
Because pin P2.8 is connected to two pads (standard pad and high-speed clock pad), it has twice the normal capacitance.

Table 17 Leakage Power Consumption XE164 (Operating Conditions apply)

Parameter	Sym-bol	Values			Unit	Note / Test Condition[1]
		Min.	Typ.	Max.		
Leakage supply current[2] Formula[3]: 600,000 × $e^{-\alpha}$; α = 5000 / (273 + B×T_J); Typ.: B = 1.0, Max.: B = 1.3	I_{LK1}	–	0.03	0.05	mA	T_J = 25°C
		–	0.5	1.3	mA	T_J = 85°C
		–	2.1	6.2	mA	T_J = 125°C

1) All inputs (including pins configured as inputs) are set at 0 V to 0.1 V or at V_{DDP} - 0.1 V to V_{DDP} and all outputs (including pins configured as outputs) are disconnected.

2) The supply current caused by leakage depends mainly on the junction temperature (see **Figure 14**) and the supply voltage. The temperature difference between the junction temperature T_J and the ambient temperature T_A must be taken into account. As this fraction of the supply current does not depend on device activity, it must be added to other power consumption values.

3) This formula is valid for temperatures above 0°C. For temperatures below 0°C a value of below 10 µA can be assumed.

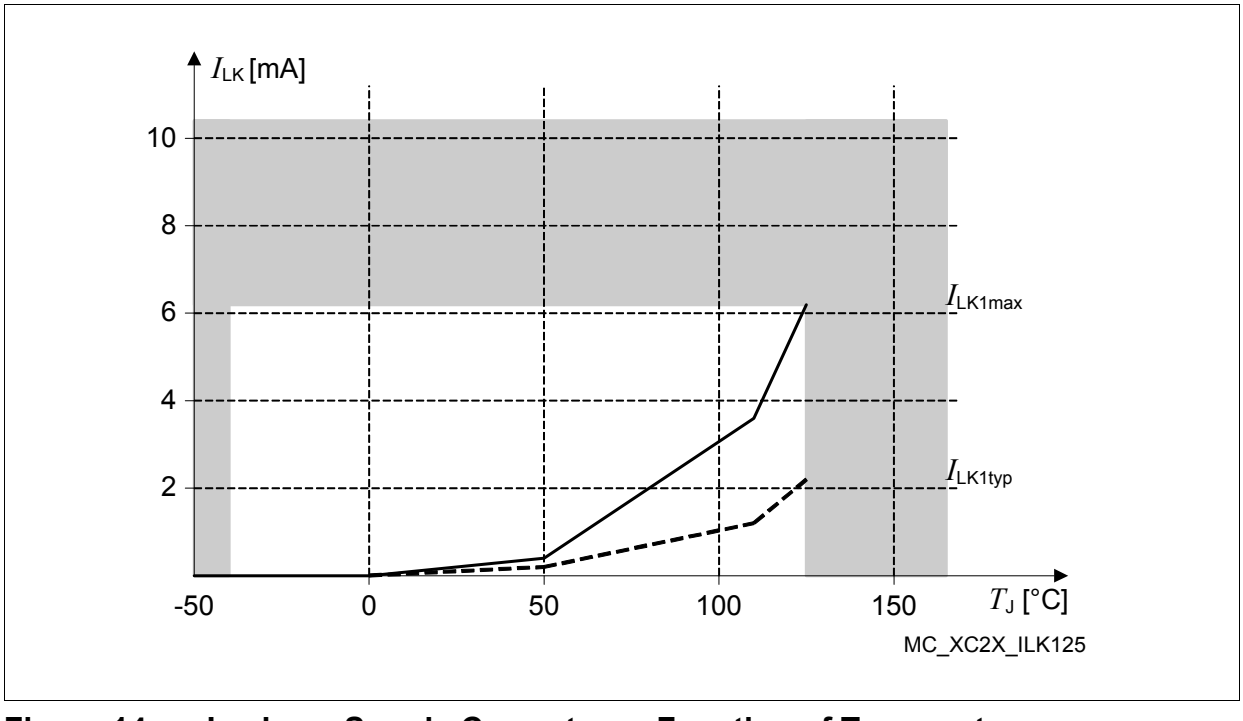

Figure 14 Leakage Supply Current as a Function of Temperature

Table 21 Coding of Bitfields LEVxV in Register SWDCON0

Code	Default Voltage Level	Notes[1)]
0000_B	2.9 V	
0001_B	3.0 V	LEV1V: reset request
0010_B	3.1 V	
0011_B	3.2 V	
0100_B	3.3 V	
0101_B	3.4 V	
0110_B	3.6 V	
0111_B	4.0 V	
1000_B	4.2 V	
1001_B	4.5 V	LEV2V: no request
1010_B	4.6 V	
1011_B	4.7 V	
1100_B	4.8 V	
1101_B	4.9 V	
1110_B	5.0 V	
1111_B	5.5 V	

1) The indicated default levels are selected automatically after a power reset.

Table 22 Coding of Bitfields LEVxV in Registers PVCyCONz

Code	Default Voltage Level	Notes[1)]
000_B	0.9 V	
001_B	1.0 V	
010_B	1.1 V	
011_B	1.2 V	
100_B	1.3 V	LEV1V: reset request
101_B	1.4 V	LEV2V: interrupt request
110_B	1.5 V	
111_B	1.6 V	

1) The indicated default levels are selected automatically after a power reset.

4.6 AC Parameters

These parameters describe the dynamic behavior of the XE164.

4.6.1 Testing Waveforms

These values are used for characterization and production testing (except pin XTAL1).

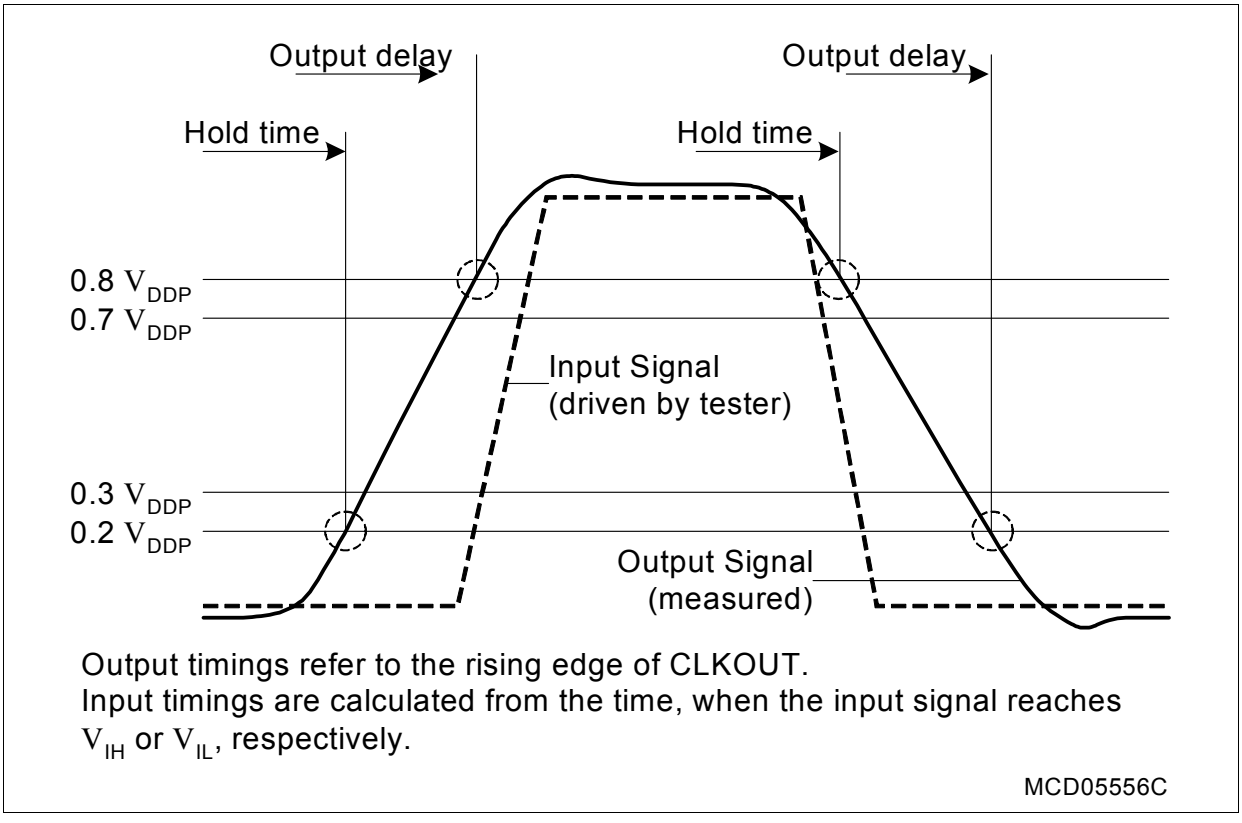

Figure 16 Input Output Waveforms

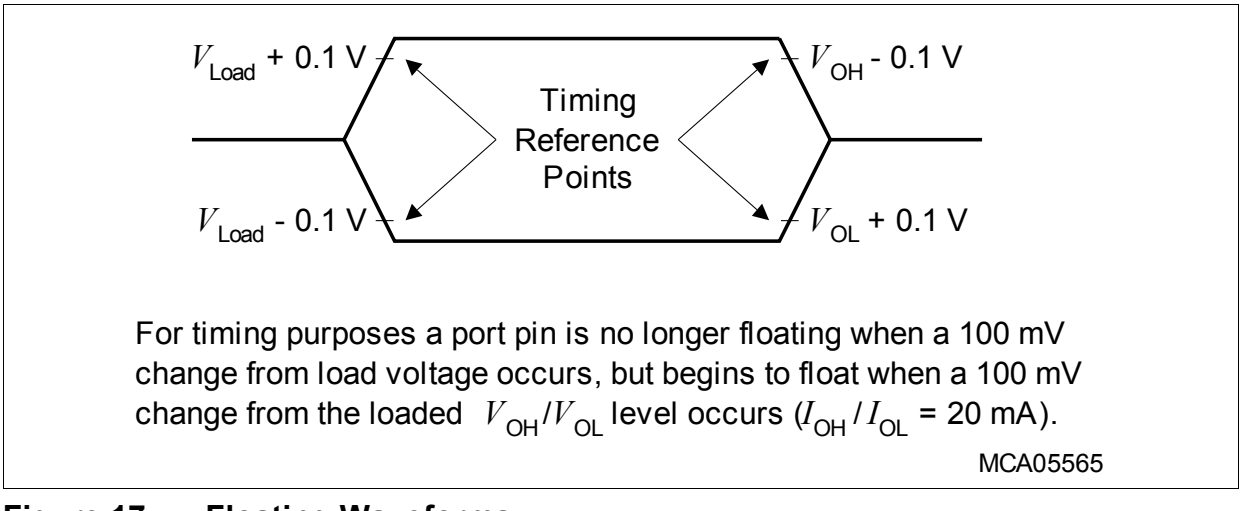

Figure 17 Floating Waveforms

Table 30 External Bus Cycle Timing for Lower Voltage Range (Operating Conditions apply)

Parameter	Symbol	Limits			Unit	Note
		Min.	Typ.	Max.		
Output valid delay for: RD, WR(L/H)	t_{10} CC	–		20	ns	
Output valid delay for: BHE, ALE	t_{11} CC	–		20	ns	
Output valid delay for: A23 … A16, A15 … A0 (on P0/P1)	t_{12} CC	–		22	ns	
Output valid delay for: A15 … A0 (on P2/P10)	t_{13} CC	–		22	ns	
Output valid delay for: CS	t_{14} CC	–		20	ns	
Output valid delay for: D15 … D0 (write data, MUX-mode)	t_{15} CC	–		21	ns	
Output valid delay for: D15 … D0 (write data, DEMUX-mode)	t_{16} CC	–		21	ns	
Output hold time for: RD, WR(L/H)	t_{20} CC	0		10	ns	
Output hold time for: BHE, ALE	t_{21} CC	0		10	ns	
Output hold time for: A23 … A16, A15 … A0 (on P2/P10)	t_{23} CC	0		10	ns	
Output hold time for: CS	t_{24} CC	0		10	ns	
Output hold time for: D15 … D0 (write data)	t_{25} CC	0		10	ns	
Input setup time for: READY, D15 … D0 (read data)	t_{30} SR	29		–	ns	
Input hold time for: READY, D15 … D0 (read data)[1)]	t_{31} SR	-6		–	ns	

1) Read data are latched with the same internal clock edge that triggers the address change and the rising edge of RD. Address changes before the end of RD have no impact on (demultiplexed) read cycles. Read data can change after the rising edge of RD.

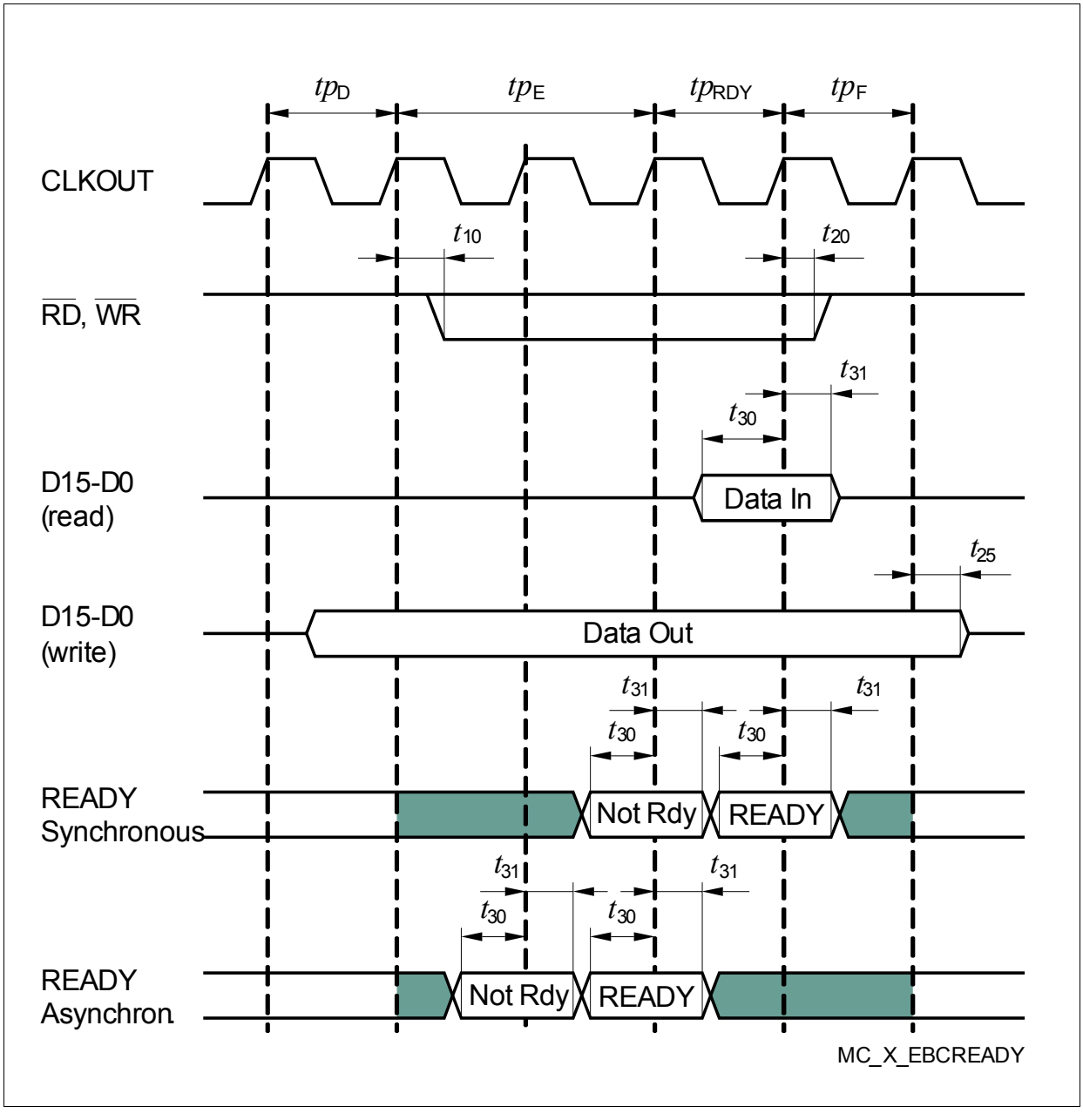

Figure 24 READY Timing

Note: If the READY input is sampled inactive at the indicated sampling point (“Not Rdy”) a READY-controlled waitstate is inserted (tpRDY),
sampling the READY input active at the indicated sampling point (“Ready”) terminates the currently running bus cycle.
Note the different sampling points for synchronous and asynchronous READY.
This example uses one mandatory waitstate (see tpE) before the READY input value is used.

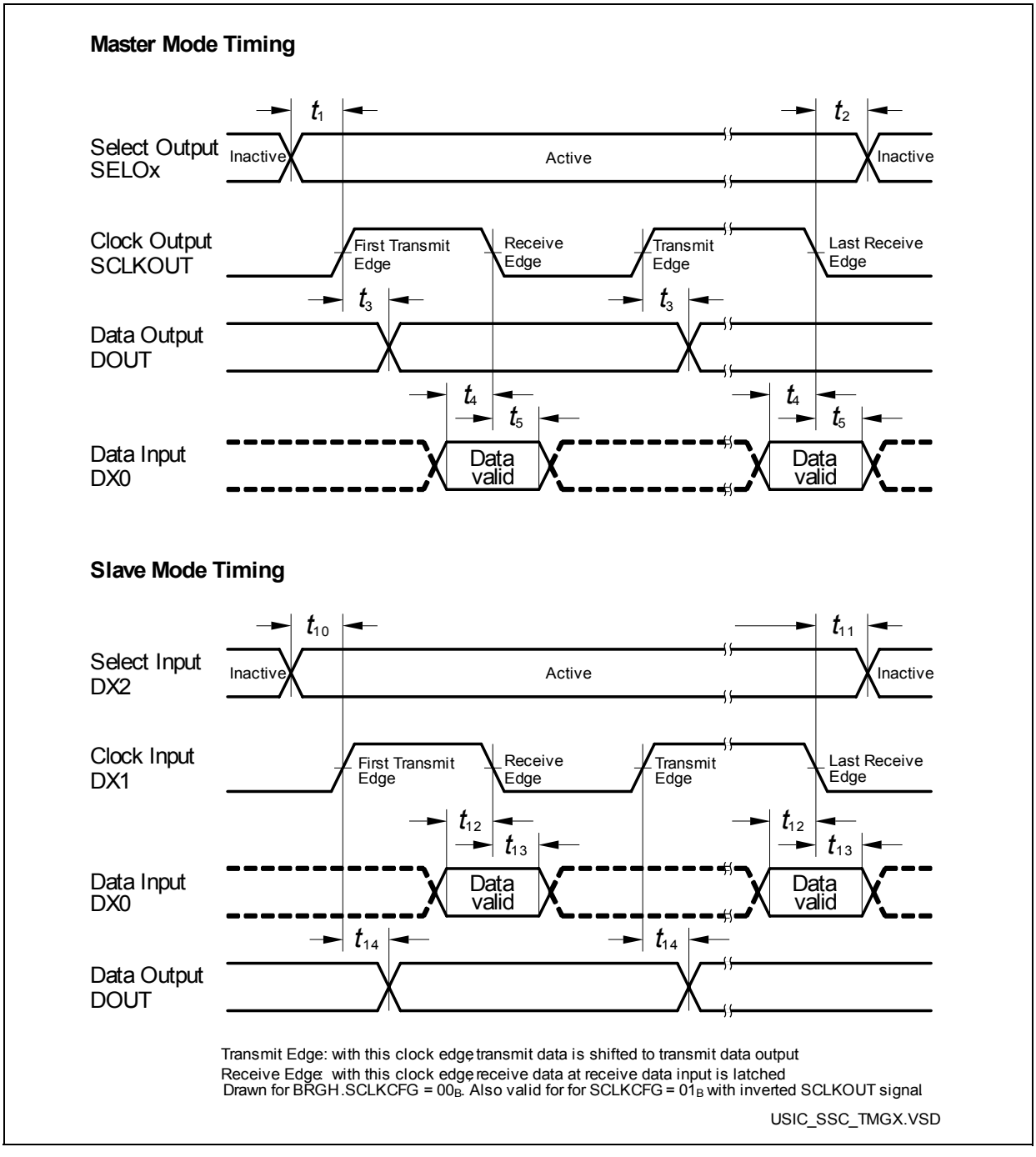

Figure 25 USIC - SSC Master/Slave Mode Timing

Note: This timing diagram shows a standard configuration where the slave select signal is low-active and the serial clock signal is not shifted and not inverted.

4.6.6 JTAG Interface Timing

The following parameters are applicable for communication through the JTAG debug interface. The JTAG module is fully compliant with IEEE1149.1-2000.

Note: These parameters are not subject to production test but verified by design and/or characterization.

Table 33 JTAG Interface Timing Parameters (Operating Conditions apply)

Parameter	Symbol	Values			Unit	Note / Test Condition
		Min.	Typ.	Max.		
TCK clock period	t_1 SR	60	50	–	ns	–
TCK high time	t_2 SR	16	–	–	ns	–
TCK low time	t_3 SR	16	–	–	ns	–
TCK clock rise time	t_4 SR	–	–	8	ns	–
TCK clock fall time	t_5 SR	–	–	8	ns	–
TDI/TMS setup to TCK rising edge	t_6 SR	6	–	–	ns	–
TDI/TMS hold after TCK rising edge	t_7 SR	6	–	–	ns	–
TDO valid after TCK falling edge[1]	t_8 CC	–	–	30	ns	C_L = 50 pF
	t_8 CC	10	–	–	ns	C_L = 20 pF
TDO high imped. to valid from TCK falling edge[1)2)]	t_9 CC	–	–	30	ns	C_L = 50 pF
TDO valid to high imped. from TCK falling edge[1)]	t_{10} CC	–	–	30	ns	C_L = 50 pF

1) The falling edge on TCK is used to generate the TDO timing.

2) The setup time for TDO is given implicitly by the TCK cycle time.